

100V Single N-Channel Enhancement-Mode MOSFET

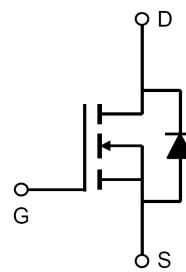
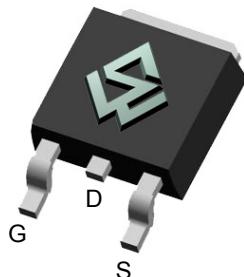
General Description

- 100V/50A
- Fully characterized Avalanche voltage and current.
- EAS 100% Test

Product Summary

- | | |
|-------------------------------|--------|
| • BV_{DSS} | 100V |
| • $R_{DS(on)}$ @ $VGS = 10V$ | < 28mΩ |
| • $R_{DS(on)}$ @ $VGS = 4.5V$ | < 30mΩ |

TO-252 D-PAK



Absolute Maximum Ratings ($T_A = 25^\circ C$ unless otherwise noted)

Parameter	Symbol	Maximum	Units
Drain-Source Voltage	V_{DS}	100	V
Gate-Source Voltage	V_{GS}	± 20	V
Drain Current ($T_A=25^\circ C$)	I_D	50	A
Drain Current ($T_C=100^\circ C$)		30	A
Pulsed Drain Current ^a	I_{DM}	150	A
Single Pulse Avalanche energy ^b	E_{AS}	62	mJ
Power Dissipation($T_C=100^\circ C$)	P_D	73	W
Junction and Storage Temperature Range	T_J, T_{STG}	-55 ~ +150	°C

Thermal Characteristics

Parameter	Symbol	Maximum	Units
Thermal Resistance, Junction-to-Case ^c	$R_{\theta JC}$	1.1	°C/W
Thermal Resistance Junction-Ambient	$R_{\theta JA}$	50	°C/W

Electrical Characteristics ($T_A = 25^\circ\text{C}$ unless otherwise noted)						
Symbol	Parameter	Conditions	Min	Typ	Max	Units
Off Characteristics						
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{\text{GS}} = 0\text{V}$, $I_D = 250\text{\mu A}$	100			V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{\text{DS}} = 100\text{V}$, $V_{\text{GS}} = 0\text{V}$			1	\mu A
I_{GSS}	Gate-Body Leakage Current	$V_{\text{GS}} = \pm 20\text{V}$, $V_{\text{DS}} = 0\text{V}$			± 100	nA
On Characteristics						
$\text{V}_{\text{GS(th)}}$	Gate Threshold Voltage	$V_{\text{DS}} = V_{\text{GS}}$, $I_D = 250\text{\mu A}$	1	1.5	2.5	V
$\text{R}_{\text{DS(ON)}}$	Drain-Source On-State Resistance	$V_{\text{GS}} = 10\text{V}$, $I_D = 20\text{A}$		19	28	$\text{m}\Omega$
		$V_{\text{GS}} = 4.5\text{V}$, $I_D = 10\text{A}$		22	28	$\text{m}\Omega$
Drain-Source Diode Characteristics						
V_{SD}	Diode Forward Voltage	$V_{\text{GS}} = 0\text{V}$, $I_S = 15\text{A}$			1.2	V
I_S	Maximum Body-Diode Continuous Current				50	A
Dynamic Characteristics						
C_{iss}	Input Capacitance	$V_{\text{DS}} = 50\text{V}$, $V_{\text{GS}} = 0\text{V}$ $f = 1.0\text{MHz}$		3120		pF
C_{oss}	Output Capacitance			150		pF
C_{rss}	Reverse Transfer Capacitance			125		pF
Switching Characteristics						
Q_g	Total Gate Charge	$V_{\text{DS}} = 50\text{V}$, $I_D = 10\text{A}$ $V_{\text{GS}} = 10\text{V}$		41		nC
Q_{gs}	Gate-Source Charge			8.6		nC
Q_{gd}	Gate-Drain Charge			28.2		nC
$\text{t}_{\text{D(ON)}}$	Turn-On Delay Time	$V_{\text{DD}} = 50\text{V}$, $\text{ID} = 1\text{A}$ $V_{\text{GS}} = 10\text{V}$ $R_{\text{GEN}} = 6.8\text{ ohm}$		20		ns
t_r	Turn-On Rise Time			180		ns
$\text{t}_{\text{D(OFF)}}$	Turn-Off Delay Time			80		ns
t_f	Turn-Off Fall Time			142		ns

- a. Repetitive rating, Pulse width limited by junction temperature $T_{J(\text{MAX})}=150\text{ }^\circ\text{C}$. Ratings are based on low frequency and duty cycles to keep initial $T_J=25\text{ }^\circ\text{C}$
- b. EAS Condition: $T_J=25\text{ }^\circ\text{C}$, $V_{\text{DD}}=15\text{V}$, $V_{\text{G}}=10\text{V}$, $L=0.5\text{mH}$, $R_g=25\Omega$
- c. The value of $R_{\theta_{\text{JC}}}$ is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, in a still air environment with $T_A = 25^\circ\text{C}$. The value in any given application depends on the user's specific board design.

Typical Characteristics

Figure 1: Output Characteristics

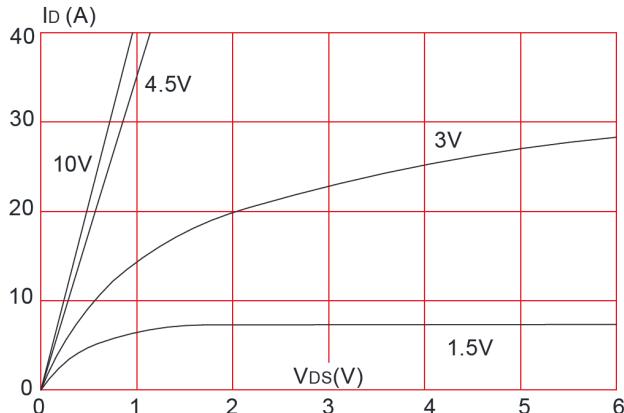


Figure 2: Typical Transfer Characteristics

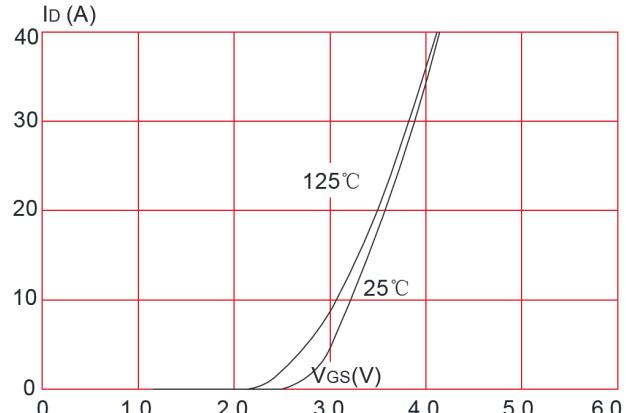


Figure 3: On-resistance vs. Drain Current

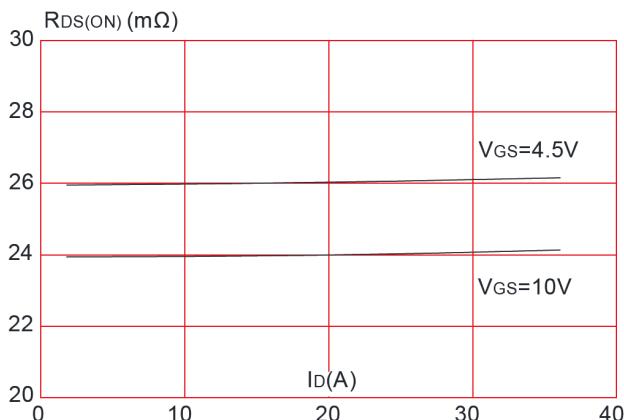


Figure 4: Body Diode Characteristics

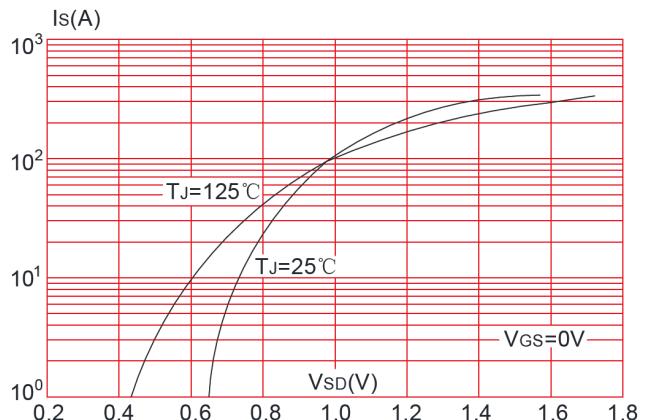


Figure 5: Gate Charge Characteristics

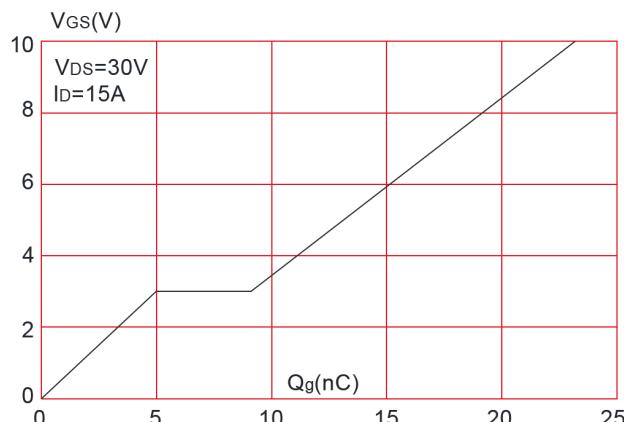
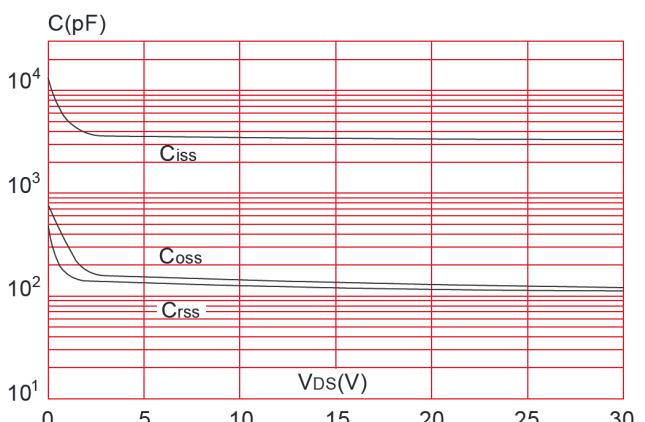


Figure 6: Capacitance Characteristics



Typical Characteristics

Figure 7: Normalized Breakdown Voltage vs. Junction Temperature

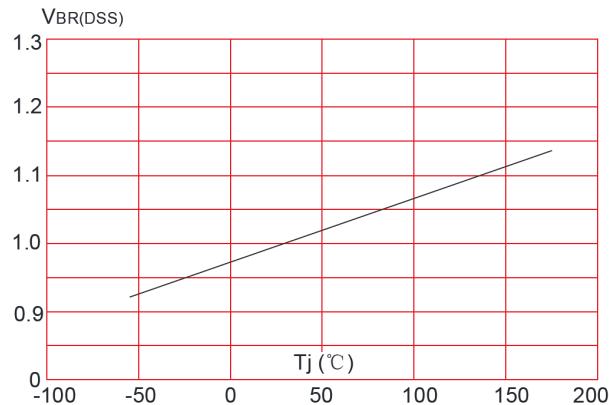


Figure 8: Normalized on Resistance vs. Junction Temperature

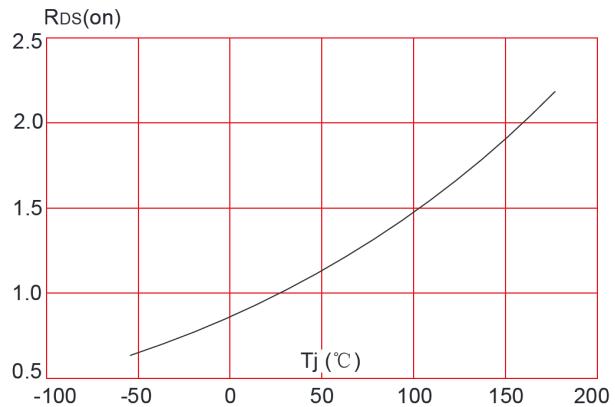


Figure 9: Maximum Safe Operating Area

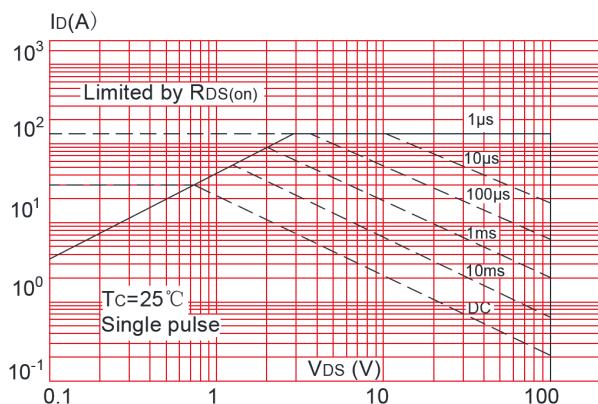


Figure 10: Maximum Continuous Drain Current vs. Case Temperature

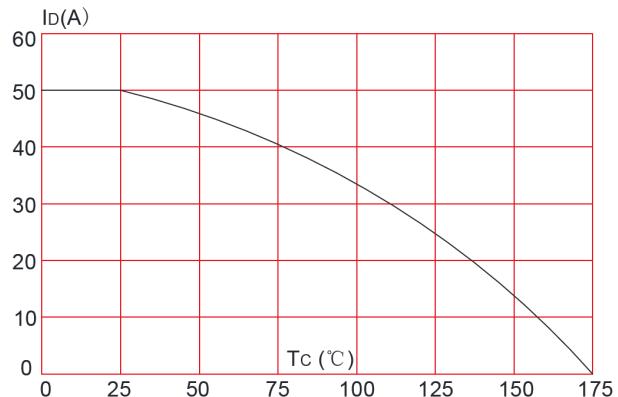
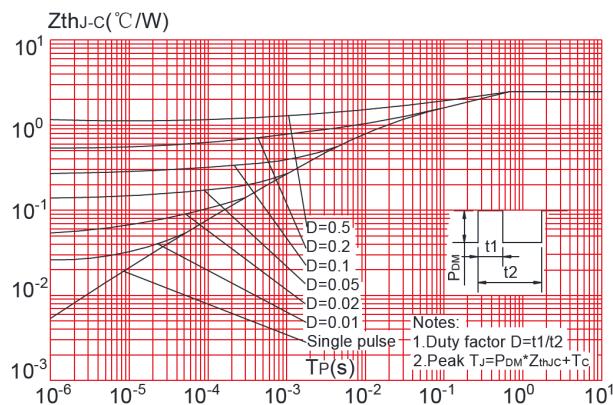
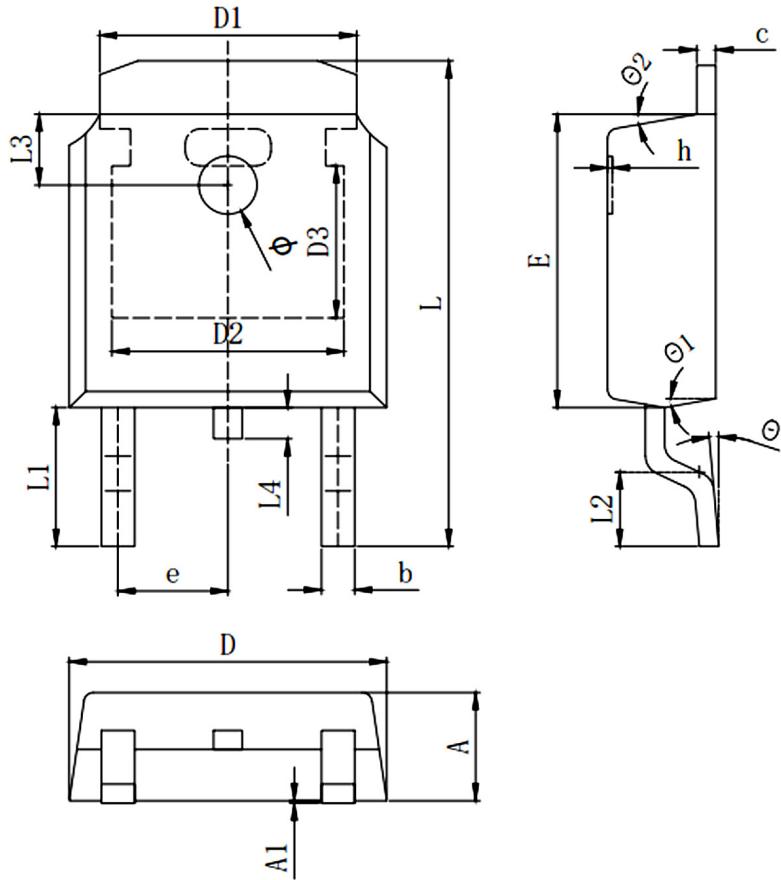


Figure 11: Maximum Effective Transient Thermal Impedance, Junction-to-Case



TO-252 D-PAK Package


Symbols	Millimeters		
	MIN.	Mom.	MAX.
A	2.200	2.300	2.400
A1	0.000		0.127
b	0.640	0.690	0.740
c(电镀后)	0.460	0.520	0.580
D	6.500	6.600	6.700
D1	5.334 REF		
D2	4.826 REF		
D3	3.166REF		
E	6.000	6.100	6.200
e	2.286 TYP		
h	0.000	0.100	0.200
L	9.900	10.100	10.300
L1	2.888 REF		
L2	1.400	1.550	1.700
L3	1.600 REF		
L4	0.600	0.800	1.000
φ	1.100	1.200	1.300
θ	0°		8°
θ1	9° TYP		
θ2	9° TYP		

单击下面可查看定价，库存，交付和生命周期等信息

>>[SiliconWisdom\(矽睿半导体\)](#)